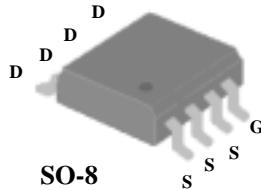


P-CHANNEL ENHANCEMENT MODE POWER MOSFET

PRODUCT SUMMARY

- Simple Drive Requirement
- Low On-resistance
- Fast Switching Characteristic

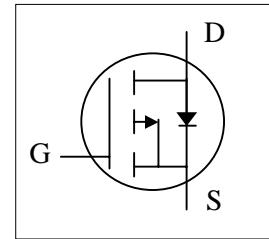


BV_{DSS}	-30V
$R_{DS(ON)}$	9mΩ
I_D	-14A

DESCRIPTION

The advanced power MOSFETs from Silicon Standard Corp. provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The SO-8 package is universally preferred for all commercial-industrial surface mount applications and suited for low voltage applications such as DC/DC converters.



Pb-free; RoHS-compliant

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	-30	V
V_{GS}	Gate-Source Voltage	± 25	V
$I_D @ T_A = 25^\circ C$	Continuous Drain Current ³	-14	A
$I_D @ T_A = 70^\circ C$	Continuous Drain Current ³	-8.9	A
I_{DM}	Pulsed Drain Current ¹	-50	A
$P_D @ T_A = 25^\circ C$	Total Power Dissipation	2.5	W
	Linear Derating Factor	0.02	W/°C
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C

THERMAL DATA

Symbol	Parameter	Value	Unit
R_{thj-a}	Thermal Resistance Junction-ambient ³	Max.	°C/W

ELECTRICAL CHARACTERISTICS

($T_J=25^{\circ}\text{C}$ unless otherwise specified)

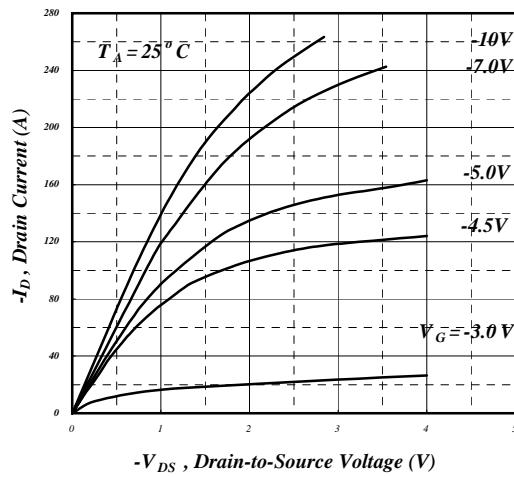
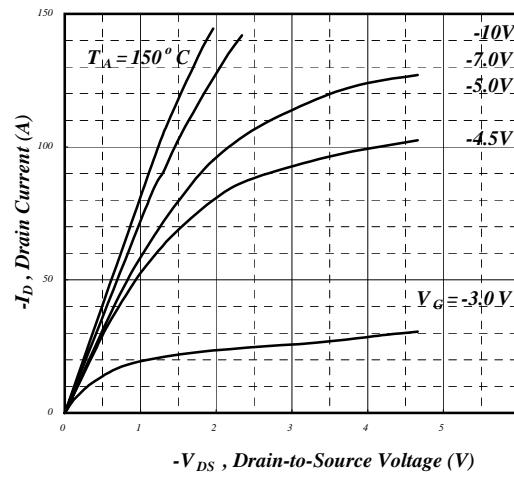
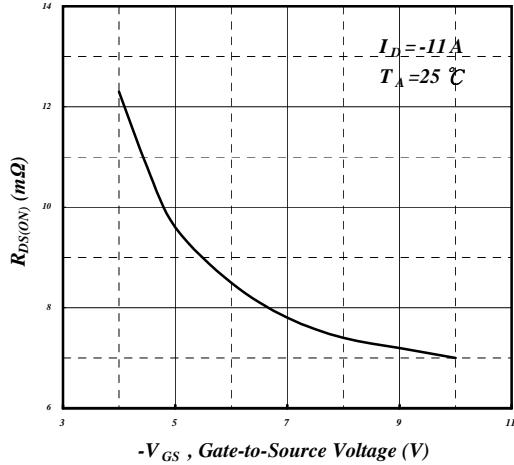
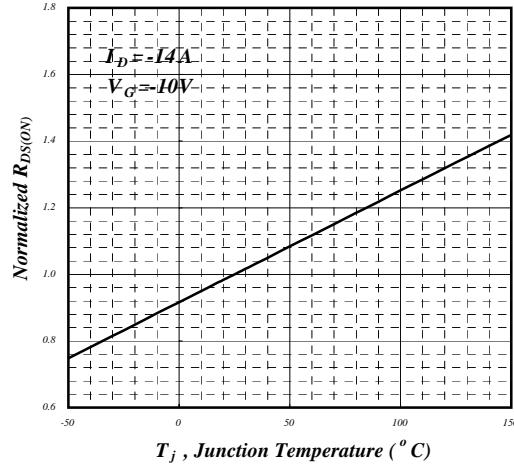
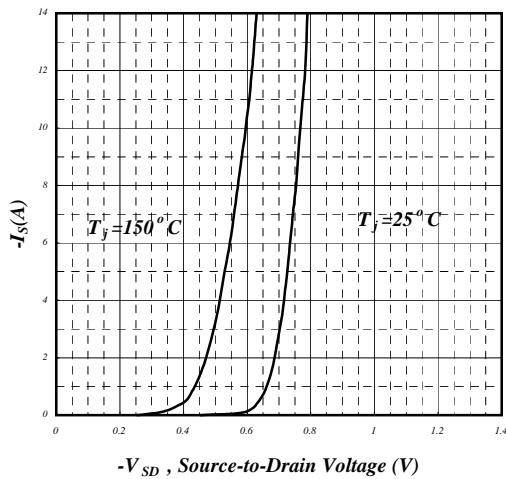
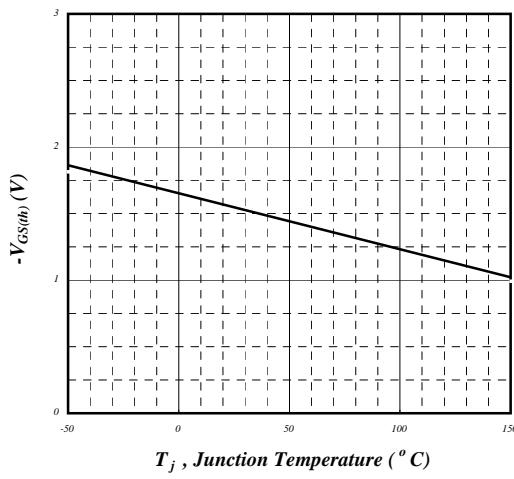
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_D=-250\mu\text{A}$	-30	-	-	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	Reference to 25°C , $I_D=-1\text{mA}$	-	-0.03	-	$^{\circ}\text{C}/\text{V}$
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=-10\text{V}$, $I_D=-14\text{A}$	-	-	9	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}$, $I_D=-11\text{A}$	-	-	13	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_D=-250\mu\text{A}$	-1	-	-3	V
g_f	Forward Transconductance	$V_{\text{DS}}=-10\text{V}$, $I_D=-14\text{A}$	-	26	-	S
I_{DSS}	Drain-Source Leakage Current ($T_J=25^{\circ}\text{C}$)	$V_{\text{DS}}=-30\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	-1	μA
	Drain-Source Leakage Current ($T_J=70^{\circ}\text{C}$)	$V_{\text{DS}}=-24\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	-25	μA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}= \pm 25\text{V}$	-	-	± 100	nA
Q_g	Total Gate Charge ²	$I_D=-14\text{A}$	-	37	60	nC
Q_{gs}	Gate-Source Charge	$V_{\text{DS}}=-24\text{V}$	-	3	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=-4.5\text{V}$	-	25	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time ²	$V_{\text{DS}}=-15\text{V}$	-	13	-	ns
t_r	Rise Time	$I_D=-1\text{A}$	-	11	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time	$R_G=3.3\Omega$, $V_{\text{GS}}=-10\text{V}$	-	58	-	ns
t_f	Fall Time	$R_D=15\Omega$	-	43	-	ns
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	2860	4580	pF
C_{oss}	Output Capacitance	$V_{\text{DS}}=-25\text{V}$	-	950	-	pF
C_{rss}	Reverse Transfer Capacitance	f=1.0MHz	-	640	-	pF

SOURCE-DRAIN DIODE

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$I_S=-2\text{A}$, $V_{\text{GS}}=0\text{V}$	-	-	-1.2	V
t_{rr}	Reverse Recovery Time ²	$I_S=-14\text{A}$, $V_{\text{GS}}=0\text{V}$,	-	48	-	ns
Q_{rr}	Reverse Recovery Charge	$dI/dt=100\text{A}/\mu\text{s}$	-	46	-	nC

Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.
- 3.Surface mounted on 1 in² copper pad of FR4 board ; $125^{\circ}\text{C}/\text{W}$ when mounted on Min. copper pad.


Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics

Fig 3. On-Resistance v.s. Gate Voltage

Fig 4. Normalized On-Resistance v.s. Junction Temperature

Fig 5. Forward Characteristic of Reverse Diode

Fig 6. Gate Threshold Voltage v.s. Junction Temperature

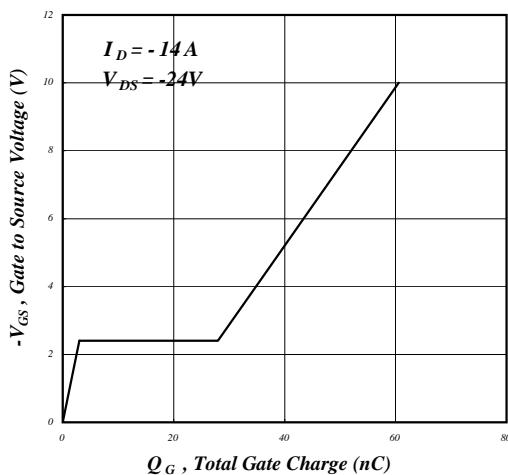


Fig 9. Gate Charge Characteristics

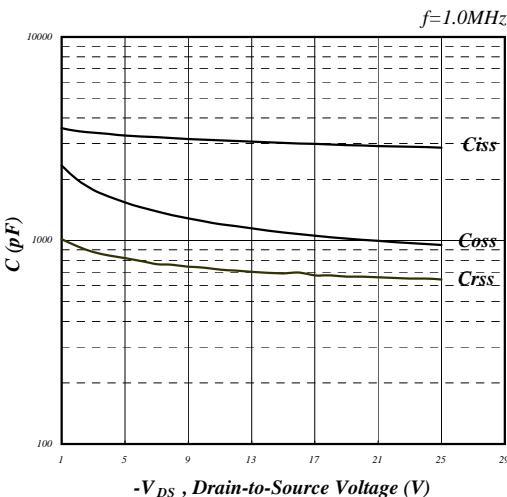


Fig 10. Typical Capacitance Characteristics

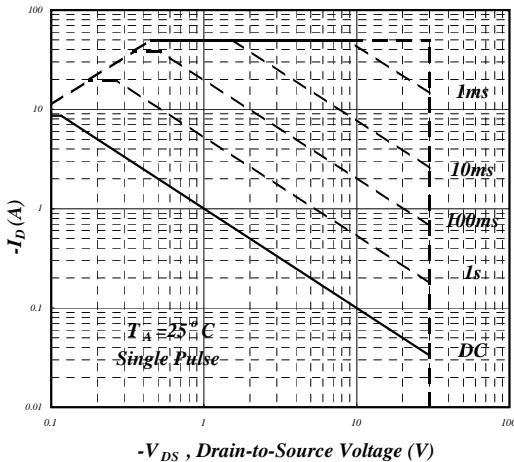


Fig 7. Maximum Safe Operating Area

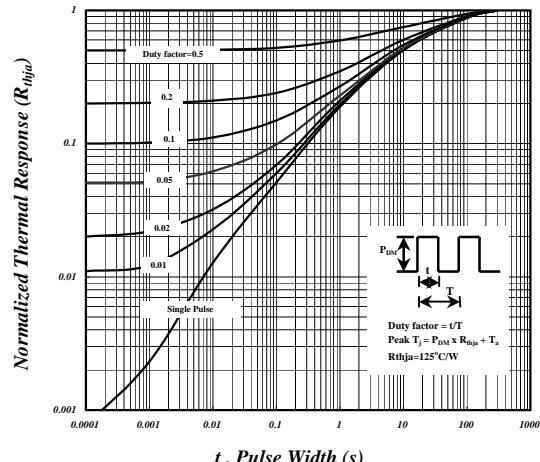


Fig 8. Effective Transient Thermal Impedance

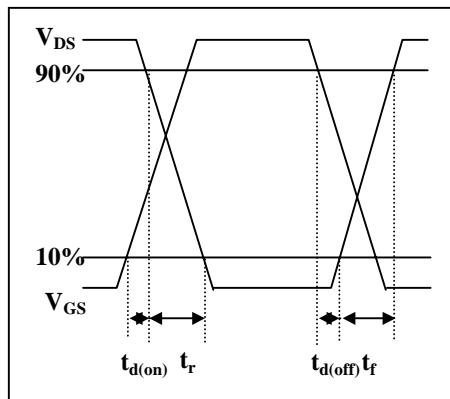


Fig 11. Switching Time Waveform

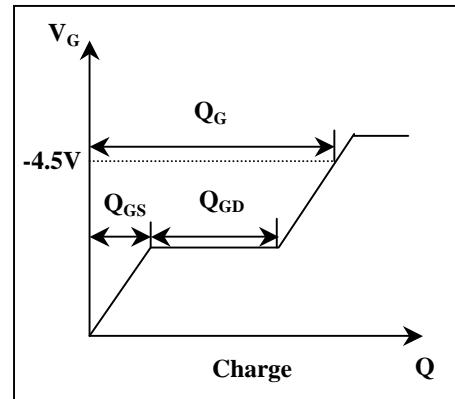


Fig 12. Gate Charge Waveform

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